



II
1
1
» Se

[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)

IEEE Xplore®
RELEASE 1.8

Welcome
United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)

Quick Links

Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

 Print Format

Your search matched **10** of **1131693** documents.
A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or enter a new one in the text box.

Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 A multianodot floating-gate MOSFET circuit for spiking neuron model
Morie, T.; Matsuura, T.; Nagata, M.; Iwata, A.;
Nanotechnology, IEEE Transactions on, Volume: 2 , Issue: 3 , Sept. 2003
 Pages:158 - 164

[Abstract] [PDF Full-Text (863 KB)] IEEE JNL

2 A conductive plastic for simulating biological tissue at microwave frequencies

Chang, J.T.; Fanning, M.W.; Meaney, P.M.; Paulsen, K.D.;
Electromagnetic Compatibility, IEEE Transactions on, Volume: 42 , Issue: 1 ,
 2000
 Pages:76 - 81

[Abstract] [PDF Full-Text (192 KB)] IEEE JNL

3 The GOLEM project: evolving hardware bodies and brains

Pollack, J.B.; Lipson, H.;
Evolvable Hardware, 2000. Proceedings. The Second NASA/DoD Workshop on
 15 July 2000
 Pages:37 - 42

[Abstract] [PDF Full-Text (408 KB)] IEEE CNF

4 A study on reliability modeling for through hole cracking failure in thermal enhanced PBGA laminate

Kobayashi, T.; Hayashida, S.;
Electronic Components and Technology Conference, 2000. 2000 Proceedings.
 50th , 21-24 May 2000
 Pages:1658 - 1660

[\[Abstract\]](#) [\[PDF Full-Text \(312 KB\)\]](#) [IEEE CNF](#)

5 Cooling strategies for embedded electronic components of wearable computers fabricated by shape deposition manufacturing

Egan, E.; Amon, C.H.;

Thermal Phenomena in Electronic Systems, 1996. I-THERM V., Inter-Society Conference on , 29 May-1 June 1996

Pages:13 - 20

[\[Abstract\]](#) [\[PDF Full-Text \(920 KB\)\]](#) [IEEE CNF](#)

6 Integrated optical nanosystems with an embedded in-line thermo-o modulator

Baglio, S.; Castorina, S.; Fortuna, L.; Bernstein, G.H.; Porod, W.;

Nanotechnology, 2003. IEEE-NANO 2003. 2003 Third IEEE Conference on , Volume: 1 , 12-14 Aug. 2003

Pages:303 - 306 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(530 KB\)\]](#) [IEEE CNF](#)

7 A novel electro-thermally driven bi-directional microactuator

Ko-Min Liao; Chin-Chiang Chueh; Rongshun Chen;

Micromechatronics and Human Science, 2002. MHS 2002. Proceedings of 2002 International Symposium on , 20-23 Oct. 2002

Pages:267 - 274

[\[Abstract\]](#) [\[PDF Full-Text \(765 KB\)\]](#) [IEEE CNF](#)

8 Thermal analysis of fingerprint sensor having a microheater array

Ji-Song Han; Kadowaki, T.; Sato, K.; Shikida, M.;

Micromechatronics and Human Science, 1999. MHS '99. Proceedings of 1999 International Symposium on , 23-26 Nov. 1999

Pages:199 - 205

[\[Abstract\]](#) [\[PDF Full-Text \(612 KB\)\]](#) [IEEE CNF](#)

9 Thermally isolated microstructures for sensors and actuators

Liwei Lin; Mu Chiao; Huey-Chi Chu;

Micro Machine and Human Science, 1995. MHS '95., Proceedings of the Sixth International Symposium on , 4-6 Oct. 1995

Pages:89 - 95

[\[Abstract\]](#) [\[PDF Full-Text \(624 KB\)\]](#) [IEEE CNF](#)

10 Investigations of the behaviour of microwave thermography antenna when coupled to layered tissue regions

Land, D.V.;

Application of Microwaves in Medicine, IEE Colloquium on , 28 Feb 1995

Pages:7/1 - 7/5

[\[Abstract\]](#) [\[PDF Full-Text \(304 KB\)\]](#) [IEE CNF](#)

[New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)



» Adva

[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)



Welcome
United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)

[Quick Links](#)

Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**

[Help](#)

- 1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.
Example: optical <and> (fiber <or> fibre) <in> ti
- 3) Limit the results by selecting Search Options.
- 4) Click Search. See [Search Examples](#)

```
(textile* <or> fabric* <or>
garment*) <and> therm* <and>
physio* <and> (simulat*)
```

Start Search **Clear**

Note: This function returns plural and suffixed forms of the keyword(s).

Search operators: <and> <or> <not> <in> [More](#)

Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)

Search Options:

Select publication types:

- IEEE Journals
- IEE Journals
- IEEE Conference proceedings
- IEE Conference proceedings
- IEEE Standards

Select years to search:

From year: **All** to **Present**

Organize search results by:

Sort by: **Relevance**
In: **Descending** order

List **15** Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.8Welcome
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- [Home](#)
- [What Can I Access?](#)
- [Log-out](#)

Tables of Contents

- [Journals & Magazines](#)
- [Conference Proceedings](#)
- [Standards](#)

Search

- [By Author](#)
- [Basic](#)
- [Advanced](#)
- [CrossRef](#)

Member Services

- [Join IEEE](#)
- [Establish IEEE Web Account](#)
- [Access the IEEE Member Digital Library](#)

IEEE Enterprise

- [Access the IEEE Enterprise File Cabinet](#)

 [Print Format](#)[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved